Notice of References Cited Application/Control No. 10/645,542 Examiner Akm Enayet Ullah Applicant(s)/Patent Under Reexamination HASEGAWA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | Α | US-5,719,978 | 02-1998 | Kakii et al. | 385/89 |
| | В | US-6,304,687 | 10-2001 | Inoue et al. | 385/14 |
| | С | US-2002/0076145 | 06-2002 | Lam et al. | 385/24 |
| | D | US-2003/0103729 | 06-2003 | Ishida, Kenzo | 385/49 |
| | Ε | US-2003/0156789 | 08-2003 | Bhardwaj et al. | 385/37 |
| | F | US-6,823,103 | 11-2004 | Lam et al. | 385/24 |
| | G | US-6,864,553 | 03-2005 | Epitaux et al. | 257/433 |
| | Н | US- | | | |
| | | US- | | | |
| | 7 | US- | | | |
| | К | US- | | | |
| | L | US- | | | |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | Z | | | | | |
| | 0 | | | | | • |
| | Р | | | | | |
| | ø | | | | | |
| | R | | | | | |
| | S | | | | | |
| | Т | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | υ | |
| | V | |
| | w | |
| | x | |

^{*}A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.